

Supplemental data

Title: Color modulation by selective excitation activated defects and complex cation distribution in $\text{Zn}_{1-x}\text{Mg}_x\text{Al}_2\text{O}_4$ nanocrystals

Megha Jain, Manju, Manish Kumar, Hyun Hwi Lee, Sung Ok Won, Keun Hwa Chae, Ankush Vij*, and Anup Thakur*

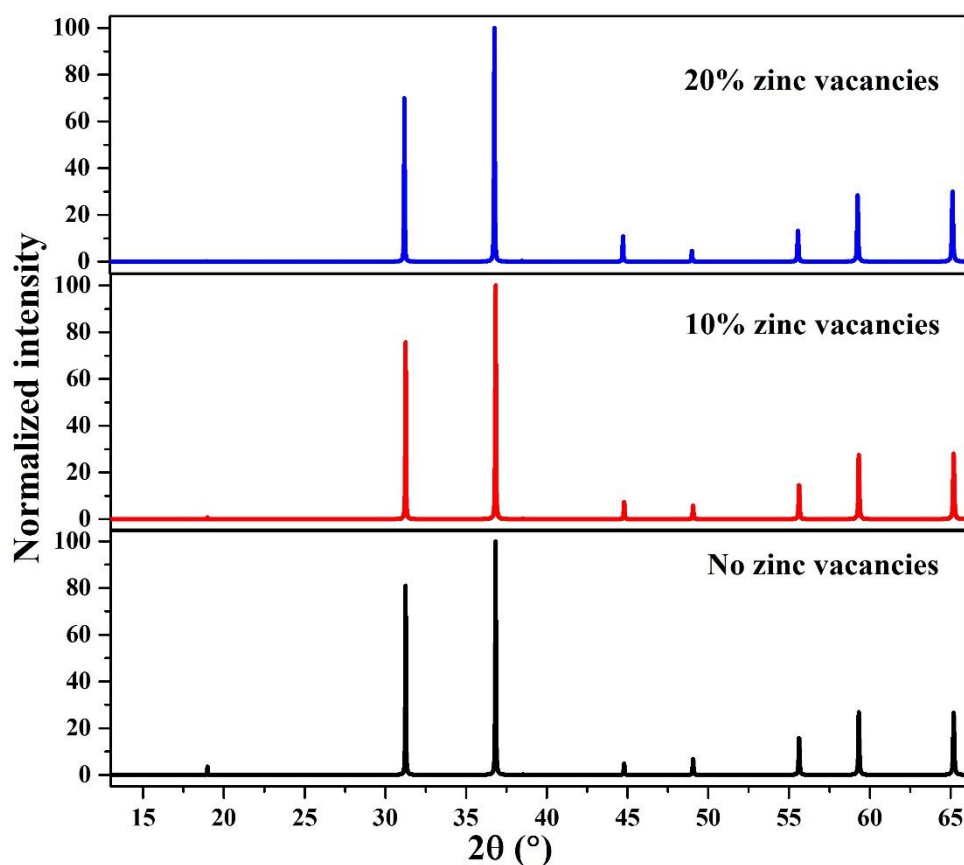


Figure S1. Simulated XRD patterns of ZnAl_2O_4 with no zinc vacancy, 10% and 20% zinc vacancies.

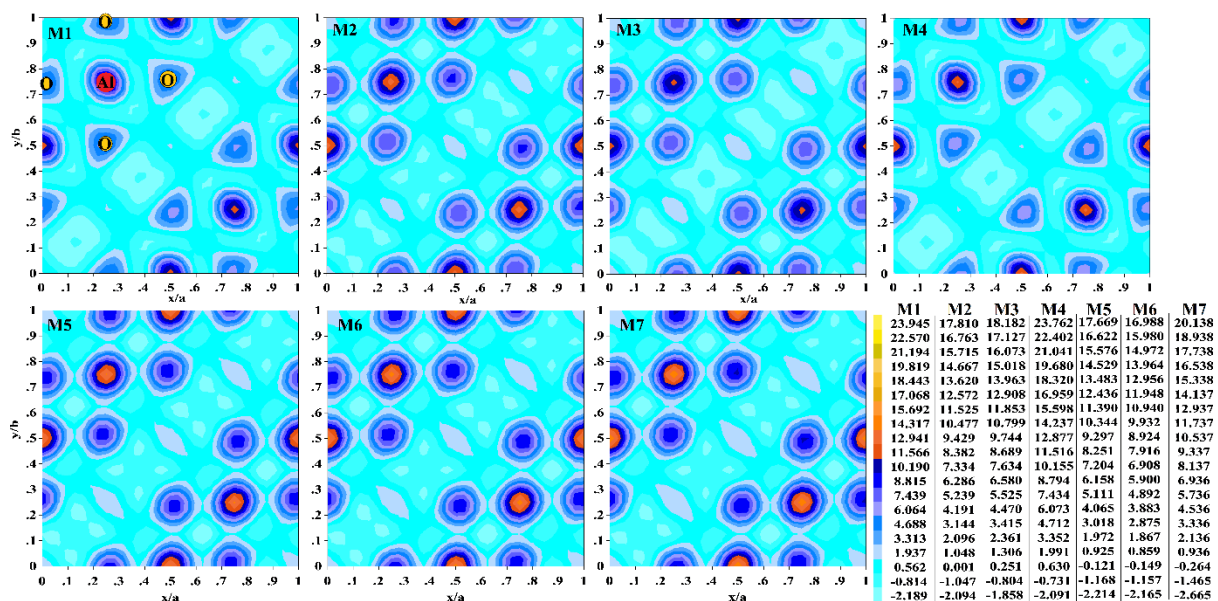


Figure S2. Observed Fourier electron density maps of all samples in the direction [001] of cubic unit cell for layer containing Al bonded to oxygen atoms (origin is considered at $\bar{3}m$ on the octahedral vacancy).

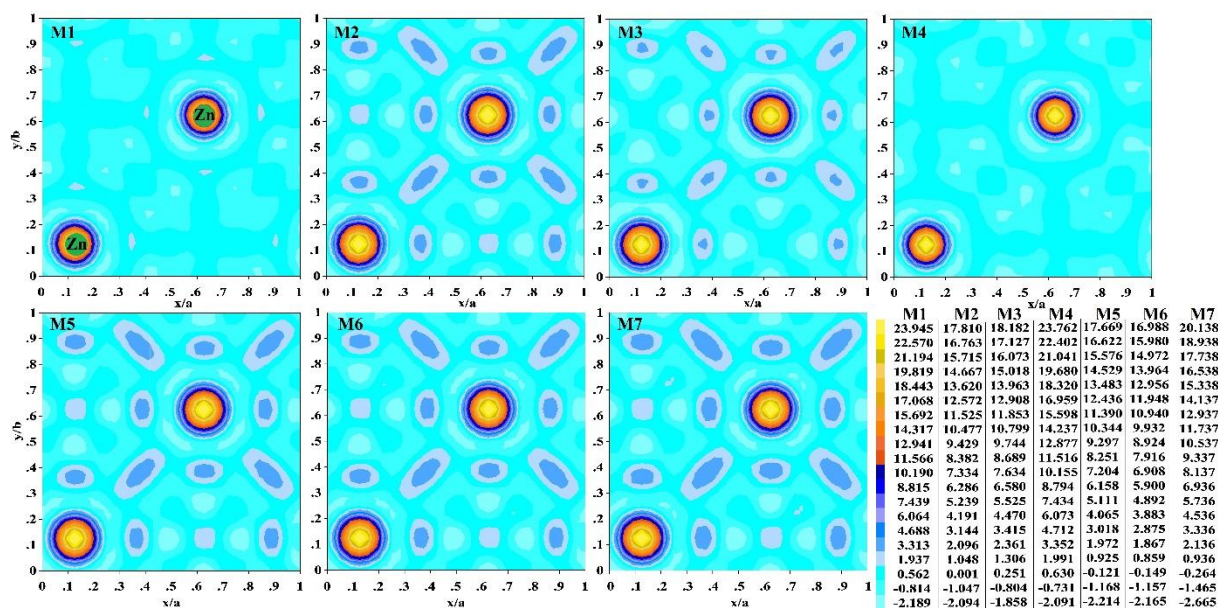


Figure S3. Observed Fourier electron density maps of all samples in the direction [001] for layer containing Zn atoms (at a height of $a/8$ of unit cell from first layer in figure S2) (origin is considered at $\bar{3}m$ on the octahedral vacancy).

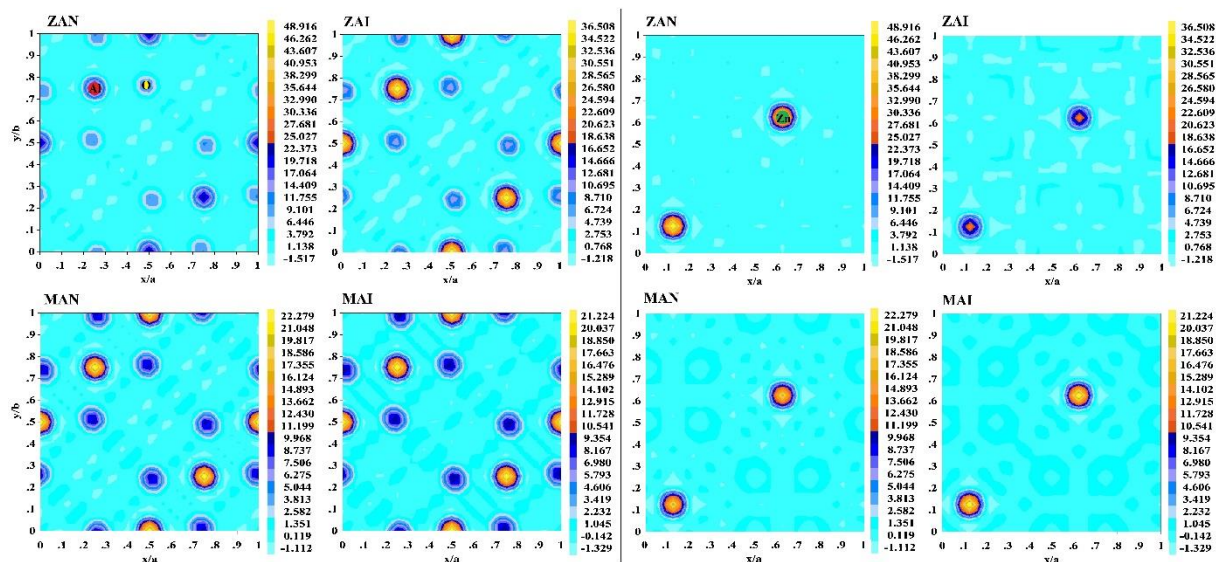


Figure S4. Simulated Fourier electron density maps of zinc aluminate (ZA) and magnesium aluminate (MA) in normal (N) and inverse (I) spinel structure along [001] direction. Density maps on the left correspond to the first layer and those on right are the layers at a height of $a/8$ from corresponding maps on left.

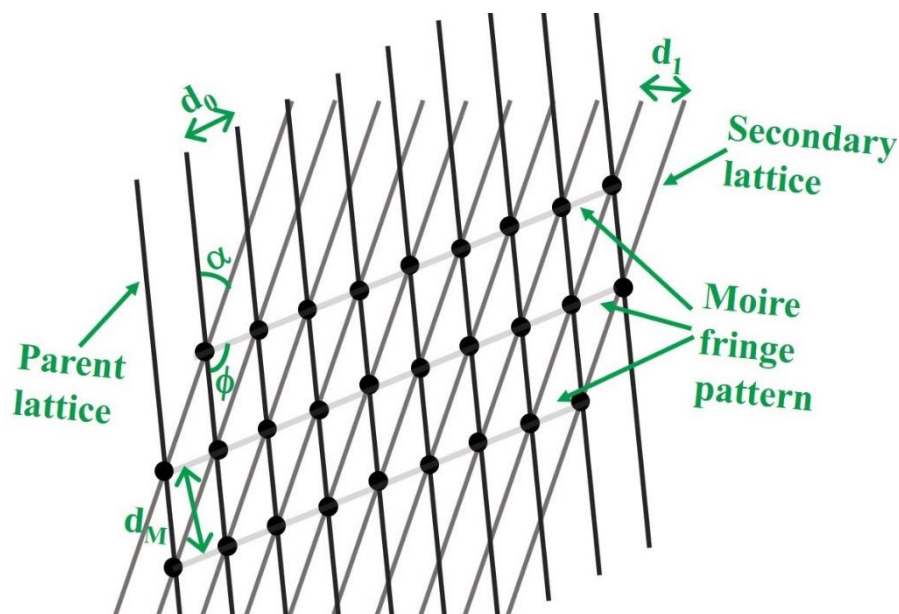


Figure S5. Illustration of Moire fringe pattern formation.

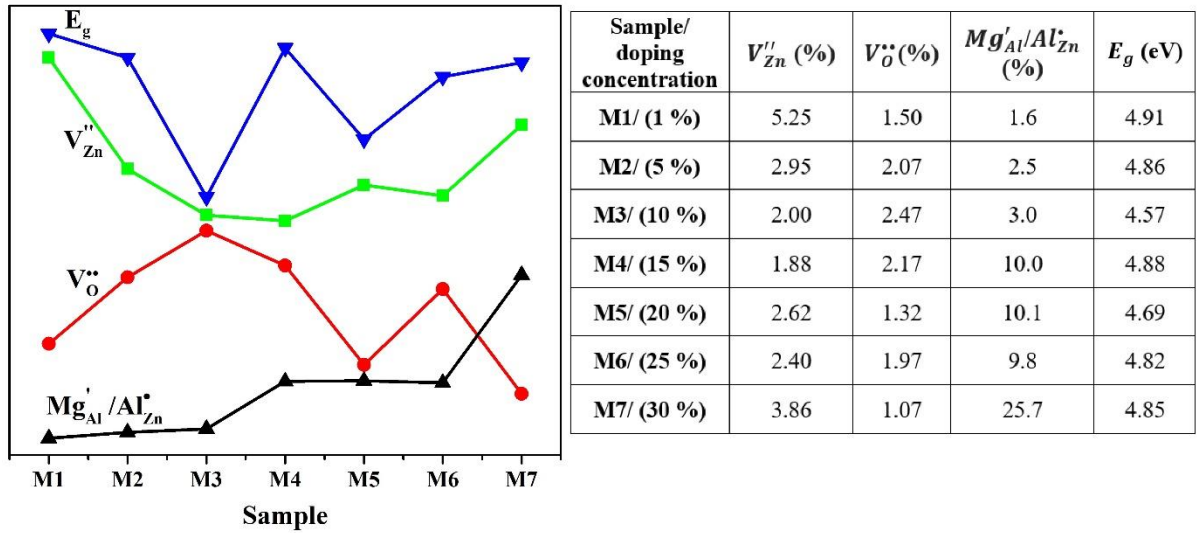


Figure S6. Relative comparison of various defects generated in $Zn_{1-x}Mg_xAl_2O_4$ samples with Mg addition and change in value of band gap. Table on the right shows the concentration of various defects calculated through Rietveld refinement, and band gap energy values for all samples.

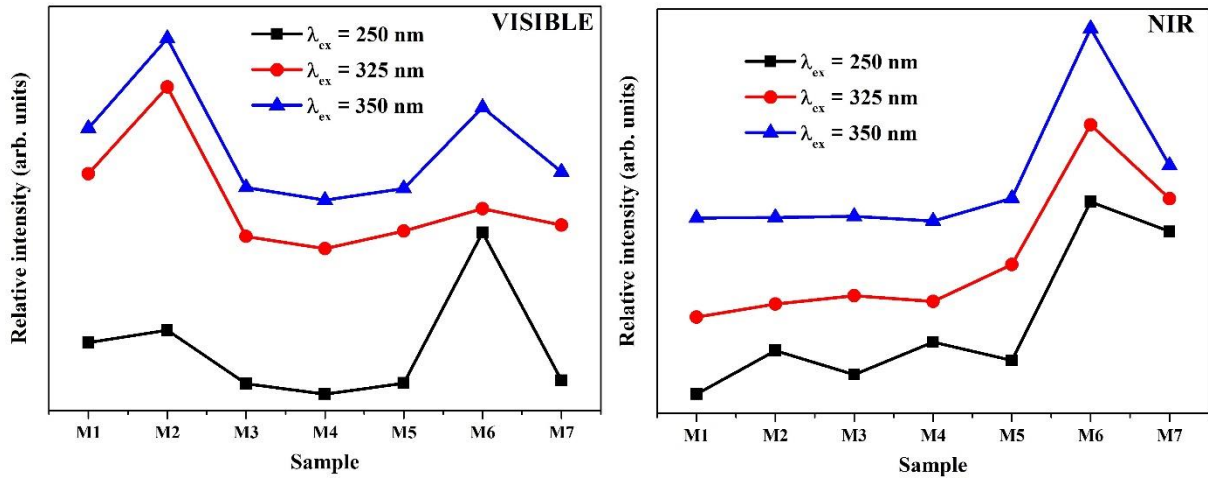


Figure S7. Trend of (a) band I and (b) band II emission integrated intensity of samples.